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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/702,459	OKUDA ET AL.	
Examiner	Art Unit	
David L. Vanik	1615	

SEARCHED			
Class	Subclass	Date	Examiner
424	489	9/16/2005	DV

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH I (INCLUDING SEAR)
	DATE	EXMR
East-See Attached	9/16/2005	DV
Pubmed-See Attached	9/16/2005	DV
Inventor Search	9/16/2005	DV
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